## Notice of References Cited Application/Control No. 10/538,203 Examiner NOAH S. WIESE Applicant(s)/Patent Under Reexamination JUESTEL ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0052595	03-2003	Ellens et al.	313/501
*	В	US-2006/0033081	02-2006	Hintzen et al.	252/301.40F
	C	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	I	US-			
	J	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	de Graaf et al. "Long wavelength Eu2+ emission in Eu-doped Y–Si–Al–O–N glasses". Journal of the European Ceramic Society. Volume 23, Issue 7, June 2003, Pages 1093-1097. Received 30 August 2001; revised 25 June 2002; accepted 6 July 2002.; Available online 18 September 2002.			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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